

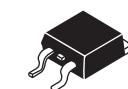


CEP75A3/CEB75A3

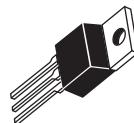
N-Channel Enhancement Mode Field Effect Transistor

FEATURES

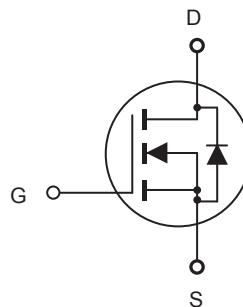
- 25V, 69A, $R_{DS(ON)} = 9\text{m}\Omega$ @ $V_{GS} = 10\text{V}$.
 $R_{DS(ON)} = 13\text{m}\Omega$ @ $V_{GS} = 4.5\text{V}$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handing capability.
- Lead free product is acquired.
- TO-263 & TO-220 package.



CEB SERIES
TO-263(DD-PAK)



CEP SERIES
TO-220



ABSOLUTE MAXIMUM RATINGS $T_C = 25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Limit | Units |
|---|----------------|------------|--------------------------|
| Drain-Source Voltage | V_{DS} | 25 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Drain Current-Continuous | I_D | 69 | A |
| Drain Current-Pulsed ^a | I_{DM} | 276 | A |
| Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$ - Derate above 25°C | P_D | 68 0.45 | W W/ $^\circ\text{C}$ |
| Operating and Store Temperature Range | T_J, T_{stg} | -55 to 175 | $^\circ\text{C}$ |

Thermal Characteristics

| Parameter | Symbol | Limit | Units |
|---|-----------------|-------|---------------------------|
| Thermal Resistance, Junction-to-Case | $R_{\theta JC}$ | 2.2 | $^\circ\text{C}/\text{W}$ |
| Thermal Resistance, Junction-to-Ambient | $R_{\theta JA}$ | 62.5 | $^\circ\text{C}/\text{W}$ |



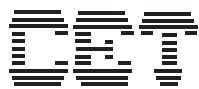
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Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Test Condition | Min | Typ | Max | Units |
|---|----------------------------|---|-----|------|------|------------------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$ | 25 | | | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}$ | | | 1 | μA |
| Gate Body Leakage Current, Forward | I_{GSSF} | $V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$ | | | 100 | nA |
| Gate Body Leakage Current, Reverse | I_{GSSR} | $V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$ | | | -100 | nA |
| On Characteristics^b | | | | | | |
| Gate Threshold Voltage | $V_{\text{GS}(\text{th})}$ | $V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$ | 1 | | 3 | V |
| Static Drain-Source On-Resistance | $R_{\text{DS}(\text{on})}$ | $V_{\text{GS}} = 10\text{V}, I_D = 35\text{A}$ | | 7 | 9 | $\text{m}\Omega$ |
| | | $V_{\text{GS}} = 4.5\text{V}, I_D = 29\text{A}$ | | 10 | 13 | $\text{m}\Omega$ |
| Dynamic Characteristics^c | | | | | | |
| Forward Transconductance | g_{FS} | $V_{\text{DS}} = 10\text{V}, I_D = 15\text{A}$ | | 12 | | S |
| Input Capacitance | C_{iss} | $V_{\text{DS}} = 15\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$ | | 1190 | | pF |
| Output Capacitance | C_{oss} | | | 280 | | pF |
| Reverse Transfer Capacitance | C_{rss} | | | 155 | | pF |
| Switching Characteristics^c | | | | | | |
| Turn-On Delay Time | $t_{\text{d}(\text{on})}$ | $V_{\text{DD}} = 15\text{V}, I_D = 1\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 6\Omega$ | | 13 | 26 | ns |
| Turn-On Rise Time | t_r | | | 5 | 10 | ns |
| Turn-Off Delay Time | $t_{\text{d}(\text{off})}$ | | | 33 | 66 | ns |
| Turn-Off Fall Time | t_f | | | 7 | 14 | ns |
| Total Gate Charge | Q_g | $V_{\text{DS}} = 15\text{V}, I_D = 20\text{A}, V_{\text{GS}} = 5\text{V}$ | | 9.8 | 13 | nC |
| Gate-Source Charge | Q_{gs} | | | 3.4 | | nC |
| Gate-Drain Charge | Q_{gd} | | | 2.7 | | nC |
| Drain-Source Diode Characteristics and Maximum Ratings | | | | | | |
| Drain-Source Diode Forward Current | I_S | | | | 69 | A |
| Drain-Source Diode Forward Voltage ^b | V_{SD} | $V_{\text{GS}} = 0\text{V}, I_S = 20\text{A}$ | | 0.85 | 1.2 | V |

Notes :

- a.Repetitive Rating : Pulse width limited by maximum junction temperature.
- b.Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
- c.Guaranteed by design, not subject to production testing.



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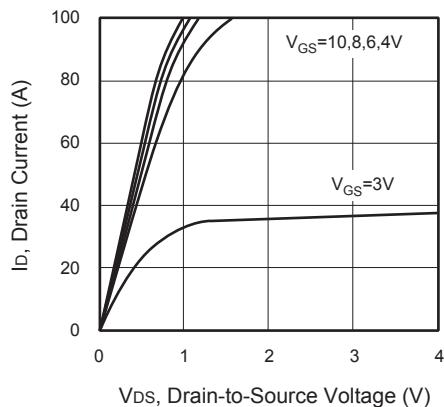


Figure 1. Output Characteristics

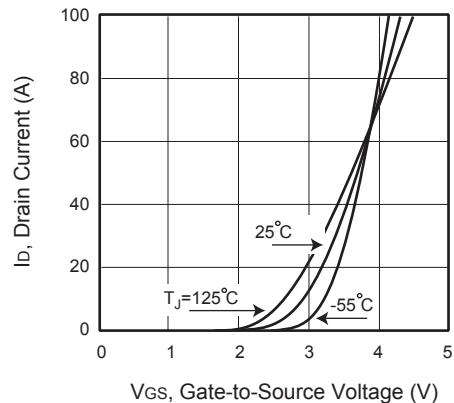


Figure 2. Transfer Characteristics

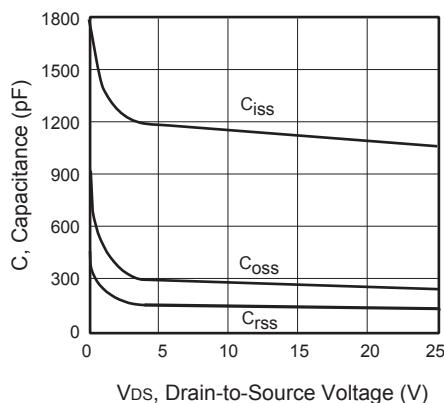


Figure 3. Capacitance

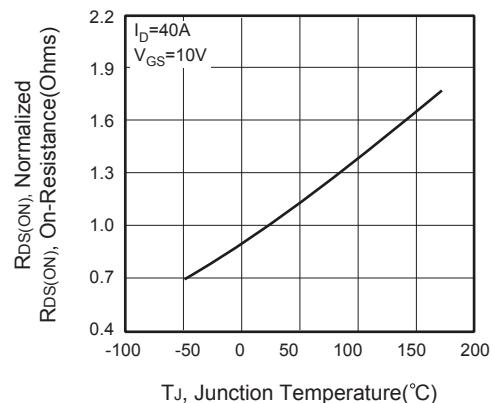


Figure 4. On-Resistance Variation with Temperature

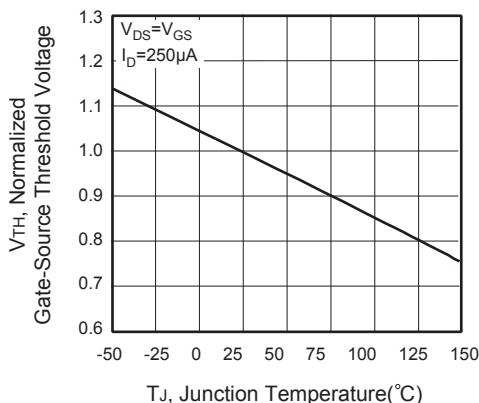


Figure 5. Gate Threshold Variation with Temperature

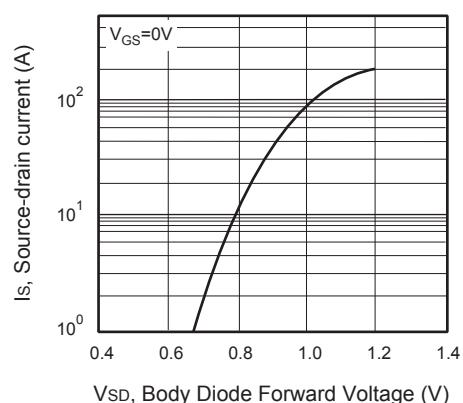


Figure 6. Body Diode Forward Voltage Variation with Source Current



CEP75A3/CEB75A3

6

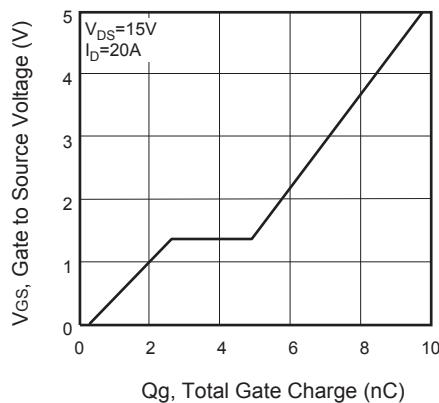


Figure 7. Gate Charge

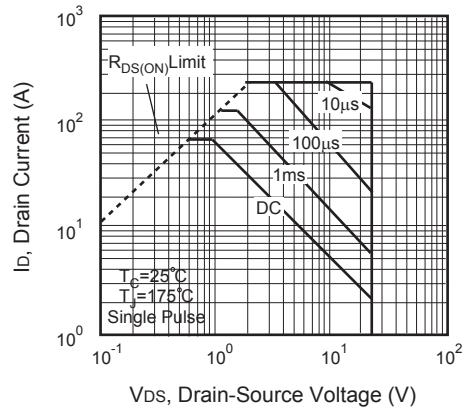


Figure 8. Maximum Safe Operating Area

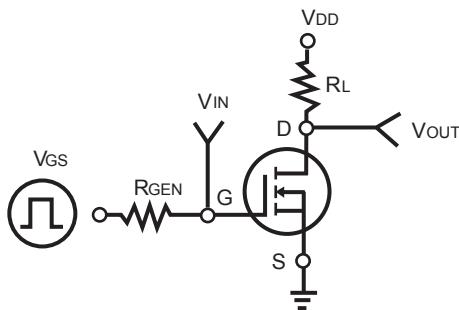


Figure 9. Switching Test Circuit

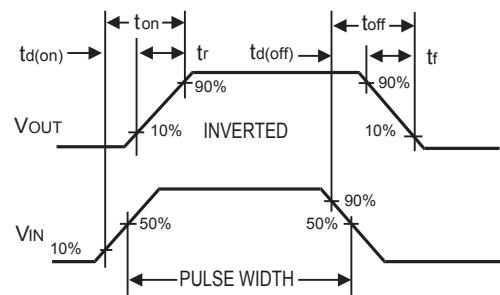


Figure 10. Switching Waveforms

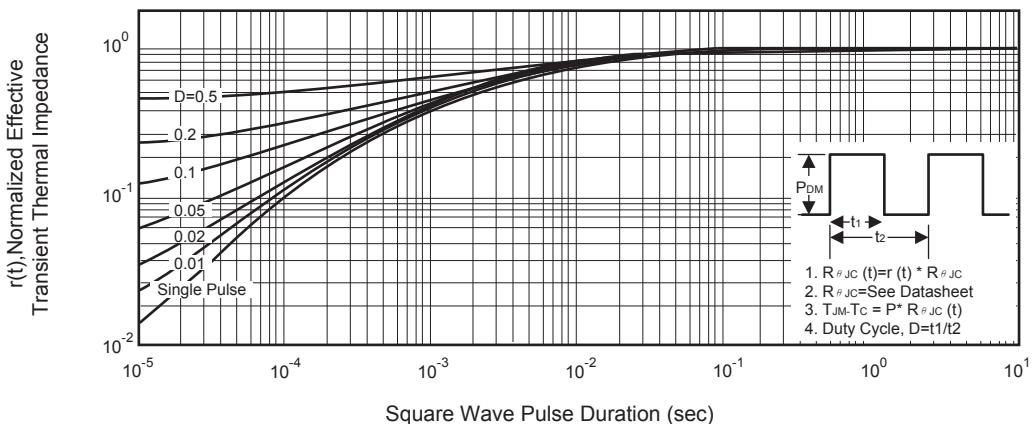


Figure 11. Normalized Thermal Transient Impedance Curve